

INFORMATION DISCLOSURE STATEMENT

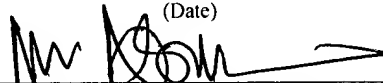
Applicant : Mark W. Miles
App. No : 09/413,222
Filed : October 5, 1999
For : PHOTONIC MEMS AND
STRUCTURES
Examiner : Hung X. Dang
Art Unit : 2873

CERTIFICATE OF MAILING

I hereby certify that this correspondence and all marked attachments are being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on

October 28, 2005

(Date)


Mark M. Abumeri, Reg. No. 43,458

Mail Stop 313(c)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Enclosed for filing in the above-identified application is a PTO/SB/08 Equivalent listing (60) references to be considered by the Examiner. Also enclosed are (21) foreign patent references and/or non-patent literature as listed on the Information Disclosure Statement.

This Information Disclosure Statement is being filed within three months of the filing date, with an RCE or before receipt of a first office action after an RCE and no fee is required.

The Commissioner is hereby authorized to charge any additional fees which may be required, or credit any overpayment, to Account No. 11-1410.

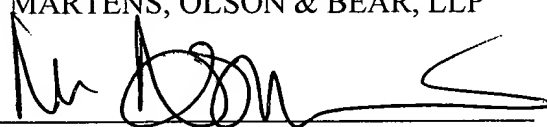
Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

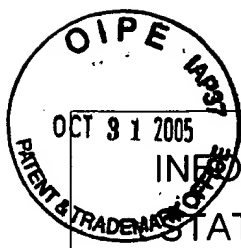
Dated:

October 28, 2005

By:



Mark M. Abumeri
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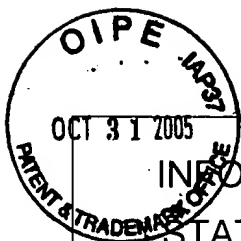


INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Multiple sheets used when necessary)	Application No.	09/413,222
	Filing Date	October 5, 1999
	First Named Inventor	Mark W. Miles
	Art Unit	2873
SHEET 1 OF 3	Examiner	Hung X. Dang
	Attorney Docket No.	IRDM.056CP

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	5,710,656	01-20-1998	Goossen	
	2	5,703,710	12-30-1997	Brinkman et al.	
	3	5,636,052	06-03-1997	Arney et al.	
	4	5,619,059	04-08-1997	Li et al.	
	5	5,579,149	11-16-1996	Moret et al.	
	6	5,500,761	03-19-1996	Goossen et al.	
	7	5,500,635	03-19-1996	Mott	
	8	5,497,172	03-05-1996	Doherty et al.	
	9	5,459,610	10-17-1995	Bloom	
	10	5,401,983	03-28-1995	Jokerst	
	11	5,381,253	01-10-1995	Sharp et al.	
	12	5,311,360	05-10-1994	Bloom	
	13	5,233,459	08-03-1993	Bozler et al.	
	14	5,231,532	07-27-1993	Magel et al.	
	15	5,168,406	12-01-1992	Nelson	
	16	5,153,771	10-06-1992	Link et al.	
	17	5,124,834	06-23-1992	Cusano et al.	
	18	5,075,796	12-24-1991	Schildkraut et al.	
	19	5,044,736	09-03-1991	Jaskie et al.	
	20	5,022,745	06-11-1991	Zahowski et al.	
	21	4,982,184	01-01-1991	Kirkwood	
	22	4,790,635	12-13-1988	Apsley	
	23	4,748,366	05-31-1988	Taylor	
	24	4,681,403	07-21-1987	TeVelde et al.	
	25	4,663,083	05-05-1987	Marks	
	26	4,531,126	07-23-1985	Sadones	
	27	4,519,676	05-28-1985	TeVelde	
	28	4,445,050	04-24-1984	Marks	
	29	4,403,248	09-06-1983	TeVelde	

Examiner Signature	Date Considered
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Multiple sheets used when necessary) SHEET 3 OF 3	Application No.	09/413,222
	Filing Date	October 5, 1999
	First Named Inventor	Mark W. Miles
	Art Unit	2873
	Examiner	Hung X. Dang
	Attorney Docket No.	IRDM.056CP

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ¹
	49	Jerman et al., "A Miniature Fabry-Perot Interferometer with a Corrugated Silicon Diaphragm Support," Sensors and Actuators A, Vol. 29, pp. 151, 1991.	
	50	Johnson, "Optical Scanners," Microwave Scanning Antennas, Vol. 1, 1964, pp. 251-261.	
	51	"Light Over Matter," June 1993. Circle No. 36.	
	52	Miles, Mark W., "A New Reflective FPD Technology Using Interferometric Modulation," Society for Information Display, 1997 Digest, Session 7.3.	
	53	Newsbreaks. "Quantum-trench Devices Might Operate at Terahertz Frequencies," Laser Focus World, May 1993.	
	54	Oliner, "Radiating Elements and Mutual Coupling," Microwave Scanning Antennas, Vol. 2, p. 131 et seq.	
	55	Raley et al., "A Fabry-Perot Microinterferometer for Visible Wavelengths," IEEE Solid-State Sensor and Actuator Workshop, June 1992, Hilton Head, SC.	
	56	Sperger et al., "High Performance Patterned All-Dielectric Interference Colour Filter for Display Applications," SID Digest 1994, pp. 81-83.	
	57	Stone, "Radiation and Optics, An Introduction to the Classical Theory," McGraw-Hill, pp. 340-343.	
	58	Walker et al., "Electron-beam-tunable Interference Filter Special Light Modulator," Optics Letter Vol. 13, No. 5, pp. 345-347, 1988.	
	59	Winton, John M., "A novel way to capture solar energy," Chemical Week, May 15, 1985, pp. 17-18.	
	60	Wu, "Design of a Reflective Color LCD Using Optical Interference Reflectors," ASIA Display 1995, October 16, 1995, pp. 929-931.	

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Multiple sheets used when necessary)

SHEET 2 OF 3

Application No.	09/413,222
Filing Date	October 5, 1999
First Named Inventor	Mark W. Miles
Art Unit	2873
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	30	4,389,096	06-21-1983	Hori et al.	
	31	4,377,324	03-22-1983	Durand et al.	
	32	4,228,437	10-14-1980	Shelton	
	33	4,099,854	07-11-1978	Decker et al.	
	34	3,955,880	05-11-1976	Lierke	
	35	3,813,265	05-28-1974	Marks	
	36	3,653,741	04-04-1972	Marks	
	37	3,443,854	05-13-1969	Weiss	
	38	3,439,973	04-22-1969	Paul et al.	
	39	2,534,846	12-19-1950	Ambrose et al.	

NON PATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ¹
	40	Akasaka, "Three-Dimensional IC Trends," Proceedings of IEEE, Vol. 74, No. 12, December 1986, pp. 1703-1714.	
	41	Aratani, et al., "Process and Design Considerations for Surface Micromachined Beams for a Tuneable Interferometer Array in Silicon," IEEE Micro. Workshop, Fort Lauderdale, FL, February 7-10, 1993, pp. 230-235.	
	42	Aratani, et al., "Surface micromachined tuneable interferometer array," Sensors and Actuators A 43, 1994, pp. 17-23.	
	43	Conner, "P-36: Hybrid Color Display Using Optical Interference Filter Array," SID Digest 1993, pp. 577-580.	
	44	Goossen, et al., "Possible Display Applications of the Silicon Mechanical Anti-Reflection Switch," Society Information Display, 1994.	
	45	Goossen, et al., "Silicon Modulator Based on Mechanically-Active Anti-Reflection Layer with 1Mbit/sec Capability for Fiber-in-the-Loop Applications," IEEE Photonics Technology Letters 6, September 1994, No. 9.	
	46	Gosch, "West Germany Graps the Lead in X-Ray Lithography," Electronics, February 5, 1987, pp.78-80.	
	47	Howard, "Nanometer-Scale Fabrication Techniques," VLSI Electronics: Microstructure Science, Vol. 5, 1982, pp. 145-153 and pp.166-173.	
	48	Jackson, "Classical Electrodynamics," John Wiley & Sons Inc., pp. 568-573.	

Examiner Signature

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